

A B S T R A C T

An electrical signal is supplied to a driving circuit section including at least one of a scanning line driving circuit and a signal line driving circuit to drive the driving circuit section and electrically charge a pixel electrode (S2). The electrically charged pixel electrode is irradiated with an electron beam to inspect the pixel electrode based on information of a secondary electron emitted from the pixel electrode irradiated with the electron beam (S3). The electrical signal is supplied to the driving circuit section through an electrical signal supply pad. The electrical signal is supplied from the electrical signal supply pad to different regions in the driving circuit section.



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